

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/674,352	LIN ET AL.	
Examiner		Art Unit		Page 1 of 1
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,251,237	10-1993	Baier, Alfred	375/346
*	B	US-5,909,426	06-1999	Liau et al.	370/203
*	C	US-7,136,111	11-2006	Kim, Joon Tae	348/614
*	D	US-2003/0112860	06-2003	Erdogan, Alper Tunga	375/229
*	E	US-2005/0084044	04-2005	Kokkonen, Mikko	375/347
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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